Electronic Supplementary Material (ESI) for Physical Chemistry Chemical Physics

SUPPLEMENTARY INFORMATION

Multiphoton Photoelectron Emission Microscopy of Single Au Nanorods: Combined Experimental and Theoretical Study of Rod Morphology and Dielectric Environment on Localized Surface Plasmon Resonances

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S1: Ellipsometric data for the ITO-coated glass coverslips

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Three ITO-coated glass coverslip samples are studied with VASE® ellipsometer (J.A. Woollam Co., Inc.). Measured ellipsometric parameters Ψ and Δ as a function of wavelength and angle of incidence for the three samples are shown in Figures S1-S3.

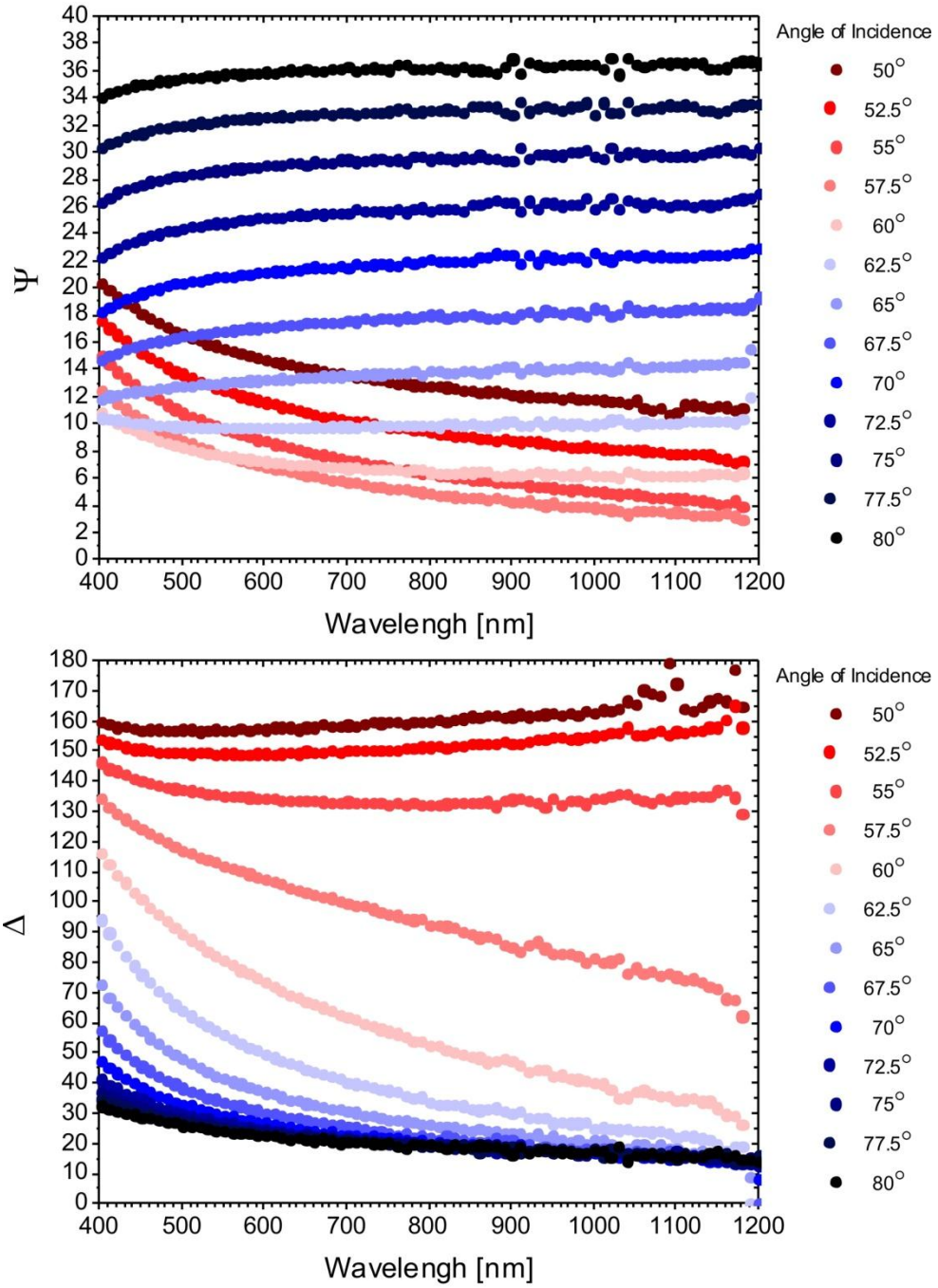

Figure S1. Ellipsometric parameters Ψ and Δ as a function of wavelength and angle of incidence for ITO-coated coverslip sample 1.

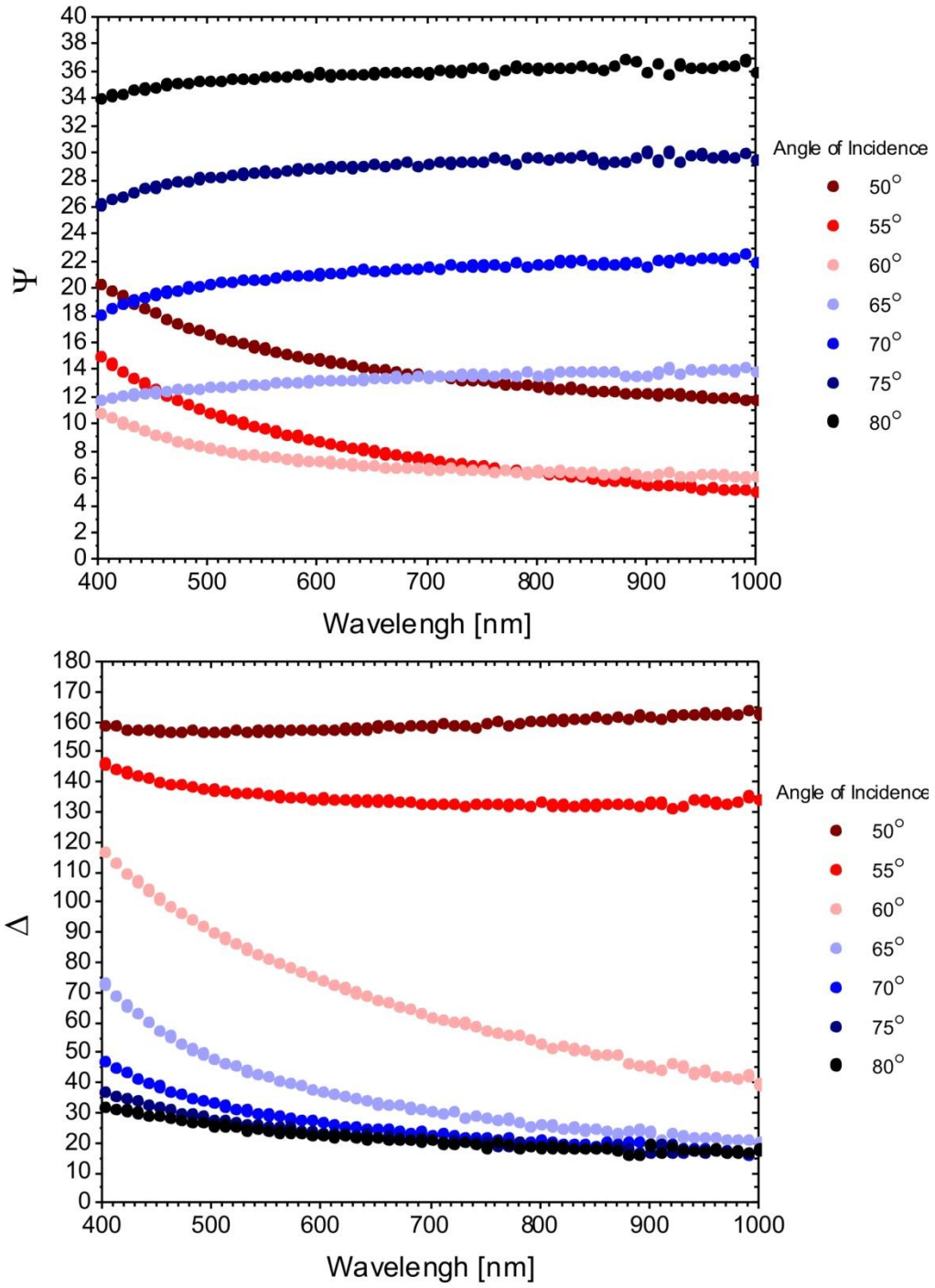

Figure S2. Ellipsometric parameters Ψ and Δ as a function of wavelength and angle of incidence for ITO-coated coverslip sample 2.

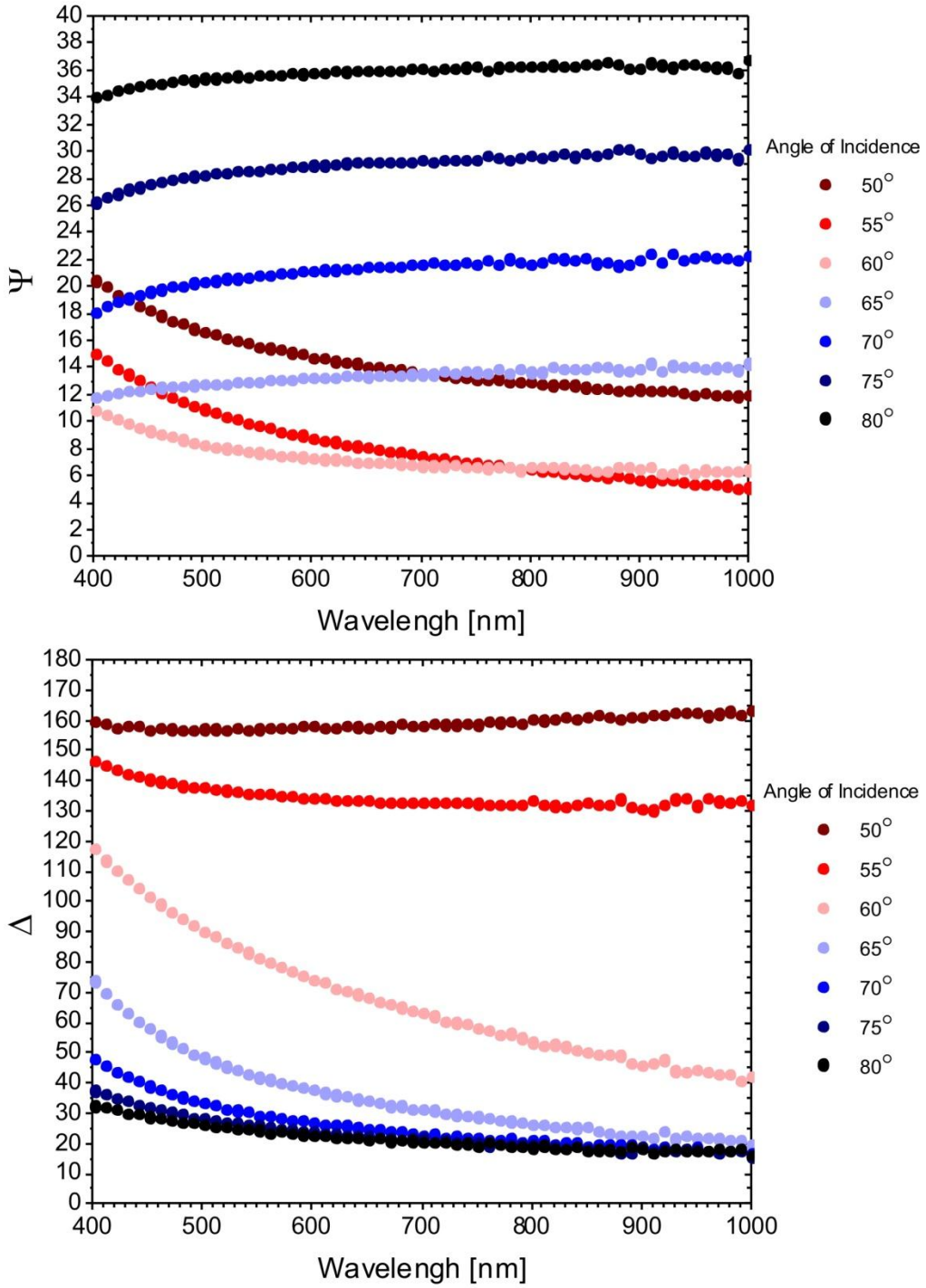

Figure S3. Ellipsometric parameters Ψ and Δ as a function of wavelength and angle of incidence for ITO-coated coverslip sample 3.